VIGO Laboratory for Electron Microscopy
Scanning electron microscope

JEOL JSM-6700F Specifications

JEOL JSM-6700F Scanning Electron Microscope	
Specifications:	
Manufacturer:	JEOL
Type:	Field Emission Scanning Electron Microscope
Resolution (secondary electron image)	1.0 nm (Acc. V. 15-30kV) 2.2 nm (1kV)
Accelerating voltage	0.5 to 2.9kV (10 V steps) 3.0 to 30 kV (100 V steps)
Magnification:	25 to 650.000
Emitter:	Cold Field Emission FEG W (310)
Imaging modes	SEI (secondary electron image) LEI (lower secondary electron image) BSE (backscattering electrons) TED (tramsmited electron detector) X-Ray Mapping
Specimen stage	Eucentric X=110mm, Y=80mm, Z=23.5mm (WD 1.5 to 25mm) T=-5 to 60° R=360°
Max. specimen size	204mm X 10mm
Operation & display system	For observation: 2 X 18.1inch, high resolution FPD For recording : 5 inch, ultrahigh resolution CRT
Auto functions	AFD (Auto Focus), ACB (Auto Contrast and Brightness Control), ASD (Auto Stigmator), AFD + ACB, Auto Photo
Accessories:	
Microanalysis:	X-Ray detector (EDS) Oxford Inca Energy 300 SEM (Line scan, X-Ray Mapping, Phase Map…)
Backscattered electrons detector:	Type YAG
Cryotransfer	Bal-Tec VCT100